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APPENDIX 3: Photographs of test setup

Conducted Emission



Photo 1



Photo 2

UL Japan, Inc. Kashima EMC Lab.

1614, Mushihata, Katori-shi, Chiba-ken, 289-0341 Japan

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Radiated Spurious Emission (30 – 1000MHz)

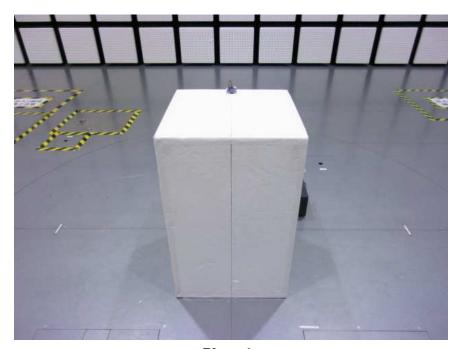


Photo 1

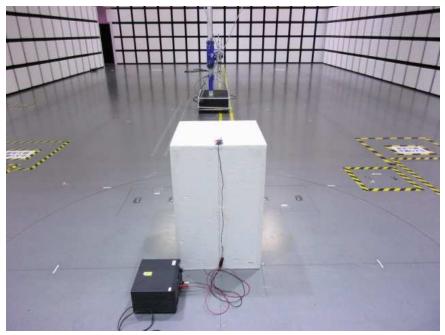


Photo 2

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Radiated Spurious Emission (1 – 26GHz)

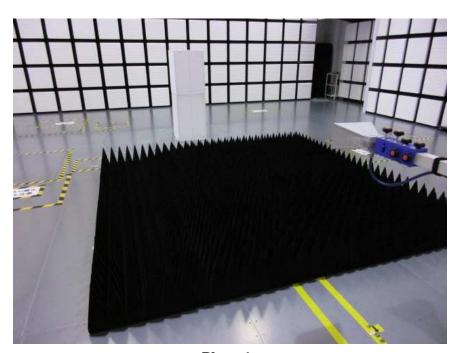


Photo 1

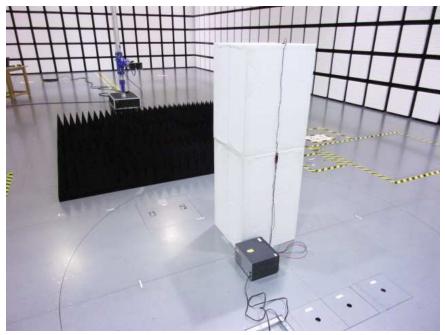


Photo 2

1614, Mushihata, Katori-shi, Chiba-ken, 289-0341 Japan

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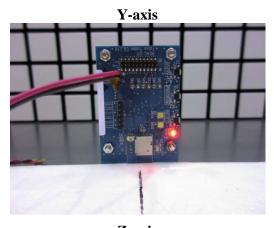
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Worst Case Position (X-axis)









^{*}Use the motherboard with no metal plate, therefore this motherboard does not affect the module test condition.

End of Report

UL Japan, Inc. Kashima EMC Lab.

1614, Mushihata, Katori-shi, Chiba-ken, 289-0341 Japan